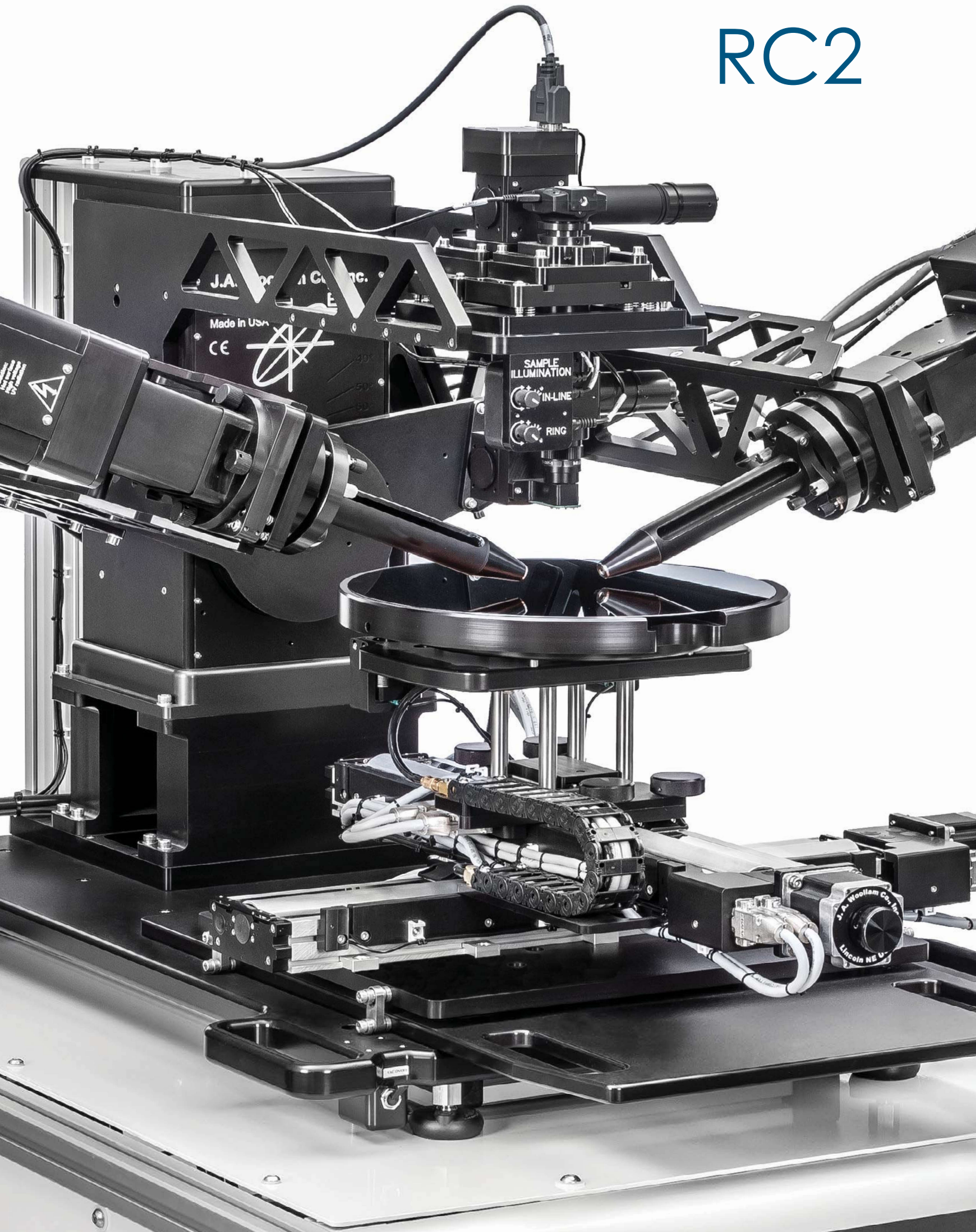


RC2



# Specifications

## System Overview

Patented dual rotating compensator ellipsometer with simultaneous CCD detection of all wavelengths, flexible system configuration.

## Measurement Capabilities

- Spectroscopic Ellipsometry (SE): Psi and Delta over their full range.
- Generalized SE: Complete 2x2 Jones matrix for anisotropic samples.
- Mueller Matrix SE: All 16 elements of the 4x4 Mueller matrix.
- Depolarization: Measure and model the non-ideal nature of your sample.
- Intensity: Both reflectance and transmittance, including anisotropic terms such as like- and cross-polarized intensities.

## Wavelength Range

|         |             |            |
|---------|-------------|------------|
| U, X:   | 210-1000 nm | 790 wvls.  |
| D:      | 193-1000 nm | 800 wvls.  |
| UI, XI: | 210-1690 nm | 1065 wvls. |
| DI:     | 193-1690nm  | 1075 wvls. |
| XI+:    | 210-2500 nm | 1065 wvls. |

## Data Acquisition Rate

Measure complete spectrum in 1/3 of a second - even for advanced data types!

## Angle Range

|                  |           |
|------------------|-----------|
| Fixed Angle      | 65°       |
| Horz. Auto Angle | 45° - 90° |
| Vert. Auto Angle | 20° - 90° |

